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Technical Compliance

No. ACS-E20108

The following product has been tested by us with the listed standards and found in compliance with the council EMC directive 2014/30/EU and Radio Equipment directive 2014/53/EU.

Applicant	: TPV Electronics (FuJian) Co., Ltd.
	Rongqiao Economic and Technological Development Zone,
	Fuqing City, Fujian Province, P.R. China
Product	: LCD MONITOR
Model No.	: 16T2; 16T2*******(* = 0-9, A-Z, a-z, +, -, /, \ or blank)
Brand	: AOC

EN 55032: 2012+AC: 2013 (Class B) Electromagnetic compatibility of multimedia equipment - Emission requirements CISPR 32: 2015 Electromagnetic compatibility (EMC) Part 3-2: Limits-Limits for harmonic current emissions(equipment input current phase) EN 61000-3-2: 2013 Electromagnetic compatibility(EMC) Part 3-2: Limits-Limits for harmonic current emissions(equipment input current phase) EN 61000-3-3: 2013 Electromagnetic compatibility(EMC) Part 3-3: Limits-Limits for harmonic current emissions(equipment input current phase) EN 61000-3-3: 2013 Electromagnetic compatibility(EMC) Part 3-3: Limits-Limitation of voltage changes, voltage fluctuations and flicker low-voltage supply systems, for equipment with rated current ≤ 16A per phas subject to conditional connection EN 55035: 2017 Electromagnetic compatibility of multimedia equipment — Immunity requirement IEC 61000-4-2: 2008 Electrostatic Discharge IEC 61000-4-2: 2010 RF Field Strength Susceptibility IEC 61000-4-2: 2014 Surge IEC 61000-4-5: 2014 Surge IEC 61000-4-6: 2013 Continuous Conducted disturban IEC 61000-4-6: 2013 Continuous Conducted disturban IEC 61000-4-8: 2009 Magnetic Field Immunity IEC 61000-4-11: 2004 Surge	
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Audix Technology (Shenzhen) Co., Ltd. EMC 部門報告專用章	
Stamp only for EMC Dept. Report Signature: <u>Bensun Chen</u> Manager Date : Jun 01, 2020	
Bensun Chen	
Manager	
Date : Jun.01, 2020 The technical compliance is based on a single evaluation of one sample of above mentioned product. It does	

The technical compliance is based on a single evaluation of one sample of above mentioned product. It does no imply an assessment of the whole production and does not permit the use of the test lab. logo.